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Principal Role of Contact Force Distribution in Determining the Thermal Conductivity of Supported Graphene

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The thermal conductivity (κ) of graphene dramatically decreases once supported on a substrate, hindering its use for thermal management. To clarify the underlying mechanisms, we investigate the κ of graphene on amorphous SiO₂ using molecular dynamics with particular attention to the graphene-substrate topography. Our analysis reveals that the suppression in κ increases with the non-uniformity of the forces acting on graphene, which tends to increase as the substrate surface roughness and graphene conformity increase. Our findings highlight the importance of the interfacial morphology on κ and can provide new guidance on the design of substrates to improve thermal transport through graphene.

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I. INTRODUCTION

Current state-of-the-art techniques have demonstrated that the thermal conductivity (κ) of free-standing graphene can be as large as 1500–5000 Wm⁻¹K⁻¹ [1–5], an order of magnitude larger κ than copper, but is reduced to around 600 Wm⁻¹K⁻¹ when supported on amorphous SiO₂ (*a*-SiO₂) at room temperature [6]. Yet while it is well-known that the κ of graphene is suppressed when supported on a substrate, the underlying mechanisms remains a subject of contention. Such an understanding will be critical to fully utilize graphene for thermal management of electronics [1].

In general, it has been thought that κ is principally influenced by the strength of the van der Waals (vdW) coupling at the graphene-substrate interface. Several previous theoretical investigations have suggested that the decrease in κ can be attributed to the dampening of the flexural acoustic (ZA) phonon modes which is tuned by the graphene-substrate interaction [7–9]. However there is some debate as to whether the strengthening of the vdW coupling at the interface either enhances [9] or diminishes [7] thermal transport.

Beyond the vdW coupling strength, it could be important to consider additional factors that vary according to the morphological differences at the graphene-substrate interface. As depicted in Figure 1, the topography of graphene may evolve due to contributions from internal and external forces. For instance, greater conformity can result from larger vdW interaction (*i.e.*, more contact area), which can yield larger internal strain (*i.e.*, more corrugation) depending on the surface roughness of the underlying substrate. As such, one possible source of the previously reported inconsistencies [7,9] could stem from the study of dissimilar graphene-substrate morphologies. We therefore postulate that the key to understanding the nature of phonon

scattering at the interface could lie in the careful portrayal of the relationship between the interfacial topography and κ .



Figure 1. Schematic demonstrating the evolution of the topography of graphene due to internal and external forces. Thermal perturbation of perfectly flat graphene induces local internal strain and thereby yields corrugated graphene; the internal strain can be described by the strain energy (E_{st}) and strain force (f_{st}) . The presence of a substrate introduces van der Waals (vdW) interactions at the interface which further influences the graphene morphology; the vdW coupling can be described by the vdW energy (E_{vdW}) and vdW force (f_{vdW}) . The grey sheet represents graphene while the yellow and red balls represent Si and O atoms, respectively, in amorphous SiO₂ (*a*-SiO₂).

In this manuscript, the variation in κ of supported graphene is comprehensively studied using classical molecular dynamics (MD) with variable SiO₂ surface roughness and graphene conformity. With particular attention to the interfacial energetics and forces, our analysis reveals that κ reduction scales directly with the non-uniformity of the forces acting on graphene, which we highlight as the "local dampening disorder." These findings underscore the importance of the careful characterization of substrate surface conditions and may prove useful in superior control over thermal transport through low-dimensional materials supported on a substrate (or embedded in matrices of dissimilar materials).

II. COMPUTATIONAL METHODS

*Gr/a-SiO*² sample preparation – Four defect-free *a*-SiO₂ slabs were constructed using Continuous Random Network Metropolis Monte Carlo (CRN-MMC) simulations following the method described in Ref. 10; each slab contained 3600 SiO₂ units with lateral thickness 7.77 × 7.98 nm², yielding a slab thickness of around 2 nm. A single graphene sheet was then placed on the top and bottom surfaces of the *a*-SiO₂ slab. The graphene/*a*-SiO₂ structures were relaxed using MD under periodic boundary conditions by the LAMMPS package [11]. For each system, we considered the non-conformed cases, which were composed of 18×32 rectangular supercells (2304 atoms), and the optimally-conformed configurations of graphene, which were determined by varying its lateral size up to a 19×33 rectangular supercell (2508 atoms) as described in the Supplementary Information and Table S1 [12]. The C-C interactions were described by an optimized Tersoff potential [4]. Additional simulation details, including the Si-O potential and C-Si and C-O Lennard-Jones parameters, can be found in Ref. 10.

Thermal conductivity of free-standing graphene – To estimate reliable values for κ at 300 K, we calculated the κ for free-standing graphene with four different lengths (L = 62.1, 124.3, 248.7 and 373.0 nm) and width 7.97 nm corresponding to a (144, 288, 576, 864)×32 rectangular supercell; periodic boundary conditions were employed in all three directions with 10 nm of vacuum space included in the vertical direction to remove interactions with the periodic image. The κ at infinite length was then extrapolated from 1/L vs $1/\kappa$ [13] in which the thickness of graphene is assumed to be 0.335 nm; such a treatment is necessary as the phonon mean free path of graphene is estimated to be ~775 nm, which is much larger than the simulation domain [1]. To obtain the κ at each *L*, we performed 10 independent reverse non-equilibrium MD (RNEMD)

simulations [14] with different initial velocity distributions for statistical accuracy. Each system was equilibrated for 100 ps within the canonical (NVT) ensemble with a Nosé-Hoover thermostat [15] and followed by 1 ns within the microcanonical (NVE) ensemble while imposing a heat flux within graphene with a velocity swap interval of 50 fs; here, all MD simulations adopted a 0.5 fs timestep. The temperature profile was extracted every 5 ps and the κ was computed from the average gradient of the linear region of the profile between the heat source and sink. Since the Debye temperature of graphene is above 2000 K [16], we included the quantum correction factor according to the procedure shown in Ref. 17.

Thermal conductivity of graphene on α -*Quartz and* a-*SiO*₂ – We used a similar approach to calculate the κ of supported graphene. Here, we replicated each graphene/a-SiO2 and graphene/ α -Quartz sample to increase the length *L* to 62.1, 77.7, 93.2, and 124.3 nm, and follow the same RNEMD methodology to calculate κ . In addition, the κ of the top and bottom graphene sheets were computed separately and considered independently.

III. RESULTS AND DISCUSSION

First, the κ of free-standing graphene at 300 K was calculated in order to establish a baseline for comparisons with supported graphene. Our predicted $\kappa = 2715 \pm 60 \text{ Wm}^{-1}\text{K}^{-1}$ is within the range of values previously reported from both experiments and simulations (1500–5000 Wm⁻¹K⁻¹) [1–5]. The thermally induced corrugations of graphene, which were quantified based on the standard deviation of the equilibrium atomic height distribution ($\sigma_{z,Gr}$), is found to be 0.8 Å at 300 K. However, we should point out that κ tends to decrease with increasing $\sigma_{z,Gr}$, which follows from compressive strain [12], as demonstrated in Fig. 2; the sensitivity of κ to corrugation may be partially responsible for the scattered κ values reported in prior experiments [1–3]. As discussed below, $\sigma_{z,Gr}$ can also vary as the substrate roughness ($\sigma_{z,sub}$) and the subsequent conformity of graphene changes.

Table I. Calculated thermal conductivity (κ), strain/vdW energy (E_{st}/E_{vdW}), and standard deviation/mean of the vdW and strain force per graphene atom (σ ($|f_{vdW,z}|$)/ μ ($|f_{vdW,z}|$) and σ ($|f_{st}|$)/ μ ($|f_{st}|$)) for graphene supported on α -Quartz and *a*-SiO₂ with the corresponding graphene ($\sigma_{z,sub}$) roughness.

Model	к	E_{vdW} /	$\sigma(f_{vdW,z}) / $	$\sigma(f_{st})$ /
$(\sigma_{ m z,Gr}/\sigma_{ m z,sub})$		E _{st}	$\mu(\mathbf{f}_{vdW,z})$	$\mu(\mathbf{f}_{st})$
	$(Wm^{-1}K^{-1})$	(eVnm ⁻²)	$(eVÅ^{-1})$	$(eVÅ^{-1})$
Gr/Quartz (0.14/0.00)	1642 ± 102	0.6514 / 0.0311	0.0016 / 0.0126	0.0093 / 0.0214
$\frac{\text{NC-Gr}/a\text{-SiO}_2}{(1.1/3.8)}$	923 ± 86	0.6231 / 0.1833	0.0252 / 0.0114	0.0159 / 0.0243
C-Gr/a-SiO ₂ (3.4/3.8)	713 ± 99	1.3577 / 0.6973	0.0354 / 0.0274	0.0377 / 0.0331

Next, the κ of graphene on atomically smooth α -Quartz (Gr/Quartz) as compared to atomically rough *a*-SiO₂ were investigated; a Monte Carlo scheme [10] was used to generate an *a*-SiO₂ slab with $\sigma_{z,sub} = 3.8$ Å. In addition, we considered the two scenarios when graphene is non-conformed (NC-Gr/*a*-SiO₂) and optimally-conformed (C-Gr/*a*-SiO₂) to *a*-SiO₂, the latter of

which was obtained after graphene was compressed bi-axially by around 5% (3%) in the *x*- (*y*-) directions. As seen in Table I, the predicted κ of the C-Gr/*a*-SiO₂ case is found to be 713 ± 99 Wm⁻¹K⁻¹, a dramatic decrease of nearly 75% from that of free-standing graphene, which is reasonably close to experimentally measured values [6]. On the other hand, the suppression is greatly mitigated in the Gr/Quartz case ($\kappa = 1642 \pm 86$ Wm⁻¹K⁻¹).

Comparing the aforementioned three cases, the κ reduction of graphene is observed to increase with the following trend: Gr/Quartz < NC-Gr/*a*-SiO₂ < C-Gr/*a*-SiO₂. A few interesting features can be found from an analysis of the interfacial energetics and forces, which are summarized in Table I. First, note that the vdW interaction energy (E_{vdw}) is comparable in the Gr/Quartz and NC-Gr/*a*-SiO₂ cases although κ significantly decreases by around 700 Wm⁻¹K⁻¹. On the other hand, the internal strain energy (E_{st}) exhibits a noticeable increase due to the increasing $\sigma_{z,Gr}$ that follows from the partial conformity of graphene to the rough surface of *a*-SiO₂.

Looking beyond the energetics, a substantial increase in the standard deviation of the vdW force $[\sigma(|f_{vdW,z}|)]$ [18] and internal strain force $[(\sigma(|f_{st}|)]$ is predicted in the NC-Gr/*a*-SiO₂ case as compared to the Gr/Quartz case. Meanwhile, the mean magnitude of the vdW force $[\mu(|f_{vdW,z}|)]$ and strain force $[\mu(|f_{st}|)]$ expectedly exhibit trends similar to the E_{vdw} and E_{st} , respectively. These results clearly demonstrate that κ should not be determined solely by the strength of the vdW coupling but also by the uniformity of forces (that depends upon the graphene-substrate morphology), herein called as the local dampening disorder.

A comparison of the C-Gr/a-SiO₂ case to the NC-Gr/a-SiO₂ case further reveals that both $E_{vdW/st}$ and $\sigma(|f_{vdW,z/st}|)$ tend to increase with κ reduction, which supports that κ is not directly

related to the magnitude of E_{vdW} . To examine the relationship between κ and the local dampening disorder in depth, we have performed subsequent calculations for NC-Gr and C-Gr supported on *a*-SiO₂ substrates with varying $\sigma_{z,sub}$.



Figure 2. Thermal conductivity (κ) as a function of surface roughness (σ_z); for free-standing graphene (red squares), σ_z refers to the corrugation of graphene ($\sigma_{z,Gr}$) while for supported graphene (green triangles and blue circles), σ_z refers to the substrate surface roughness ($\sigma_{z,sub}$). The inset compares $\sigma_{z,Gr}$ to that of $\sigma_{z,sub}$ for each supported graphene case; points far below the black diagonal line indicate poor conformity.

Figure 2 shows the predicted κ of graphene on *a*-SiO₂ as a function of $\sigma_{z,sub}$. As $\sigma_{z,sub}$ for different C-Gr/*a*-SiO₂ samples (blue circles) increases from 2.00 to 4.09 Å, the predicted κ tends to decrease from 935 ± 101 to 562 ± 68 Wm⁻¹K⁻¹, which is a reasonable range given the scattered values reported in both experiments [3,6] and simulations [19]. The κ of NC-Gr/*a*-SiO₂ (green triangles) is similarly repressed from 1096 ± 101 to 923 ± 86 Wm⁻¹K⁻¹, although to a lesser extent than the C-Gr/*a*-SiO₂ cases. When compared to free-standing graphene (red squares), it is evident that the presence of the substrate suppresses κ by more than a factor of two. Furthermore, these results illustrate that the surface roughness of *a*-SiO₂ and the conformity of graphene can

strongly influence κ ; specifically, we find that κ decreases as $\sigma_{z,sub}$ increases, and more so when graphene is well-conformed to *a*-SiO₂.



Figure 3. Relationship between the standard deviation of the applied vdW and strain force (σ_{force}) and the thermal conductivity (κ).

We next examine the relationship between the local dampening disorder induced on supported graphene and κ in Figure 3, in which the relative importance of $\sigma(|f_{vdW,z}|)$ and $\sigma(|f_{st}|)$ were considered. Figure 3 depicts $\sigma(|f_{vdW,z}|)$ and $\sigma(|f_{st}|)$ as a function of κ for both C-Gr/*a*-SiO₂ and NC-Gr/*a*-SiO₂. Remarkably, we observe that the decrease in κ distinctly follows an increase in both $\sigma(|f_{vdW,z}|)$ and $\sigma(|f_{st}|)$, although the dependence on $\sigma(|f_{vdW,z}|)$ seemingly dominates in these cases; on the other hand, κ is revealed to be insensitive to both $\mu(|f_{vdW,z}|)/\mu(|f_{st}|)$ and E_{vdW}/E_{st} [12]. Recall that the optimal conformation of graphene tends to be less coarse than the underlying substrate surface [10], which can result in irregularities in the contact force distribution while the strain force distribution is comparatively smoother. However, we may conceive a situation in which graphene and the underlying substrate are corrugated with uniform separation, in which

case it is possible that $\sigma(|f_{st}|)$ is comparatively larger than $\sigma(|f_{vdW,z}|)$. Nonetheless, these results demonstrate that when graphene is supported on a substrate, κ strongly depends on the degree of uniformity of the force distribution along the graphene sheet, which in turn suggest that the broad range of experimental values for the κ of supported graphene may be attributed to differences in the morphology of the graphene-substrate interface.



Figure 4. Spatial distribution of eigenmodes with phonon participation ratio < 0.3 ($|\Phi_z|$) for the (a) Gr/Quartz, (b) NC-Gr/*a*-SiO₂, and (c) C-Gr/*a*-SiO₂ cases. Color maps of the spatially-resolved distance between graphene and the substrate for the (d) Gr/Quartz, (e) NC-Gr/*a*-SiO₂, and (f) C-Gr/*a*-SiO₂ cases.

An analysis of the spatially-resolved vibrational eigenmodes (λ) can further reveal the nature of κ suppression in the presence of different substrate/conformity conditions. The phonon participation ratio [20] (p_{λ}) for each λ was first calculated for the three cases (of Gr/Quartz, NC-Gr/a-SiO₂, C-Gr/a-SiO₂ from Table 1) as follows:

$$p_{\lambda} = N \sum_{i} \left(\sum_{j=x,y,z} \epsilon^*_{ij,\lambda} \epsilon_{ij,\lambda} \right)^2$$

where $\varepsilon_{ij,\lambda}$ is the vibrational eigenvector component for atom *i* in direction *j* over all atoms *N*; p_{λ} corresponds to the fraction of atoms participating in the λ^{th} mode and varies between unity and zero for completely delocalized and localized phonon states, respectively. We find that the calculated suppression in κ , which varies as Gr/Quartz < NC-Gr/*a*-SiO₂ < C-Gr/*a*-SiO₂, coincides with the apparent localization of low-energy acoustic (< 400 cm⁻¹) and high-energy optical (> 1200 cm⁻¹) phonon modes [12].

The fractional distribution (per atom) of localized λ (denoted as $\Phi_{ij,r}$) within the range Γ = { $\lambda : p_{\lambda} < 0.3$ } can be computed from [21]

$$\Phi_{ij,\Gamma} = \frac{\sum_{\epsilon \Gamma} \epsilon^*_{ij,\lambda} \epsilon_{ij,\lambda}}{\sum_{i'} \sum_{\lambda \in \Gamma} \epsilon^*_{i'j,\lambda} \epsilon_{i'j,\lambda}}$$

and indicates the relative concentration (or contribution) of atom *i* to the λ modes in Γ . The $\Phi_{ij,r}$ (i = z) throughout the graphene lattice is depicted in Fig. 4(a)–(c). It is evident that in the Gr/Quartz case [Fig. 4(a)], $\Phi_{ij,r}$ is uniformly distributed across the lattice, showing that all atoms are nearly equally involved as an extended mode; according to our previous analysis, this is related to the flat and homogeneous nature of the graphene-substrate topography, as depicted by a color map of the spatially-resolved distance between graphene and the substrate in Fig. 4(d). The NC-Gr/*a*-SiO₂ case [Fig. 4(b)] contrastingly displays a distinct discontinuity in which the central atoms [dark yellow to red] are seen to contribute significantly more to these phonon modes than the outer atoms [light yellow to white] and indicate a clear departure from an extended state. The corresponding separation distance color map [Fig. 4(e)] demonstrates that these regions with localized modes are confined by the contact between graphene and the substrate surrounding a void space due to poor conformation; we note, however, that these modes remain fairly diffuse over the pocket region likely due to the smoothness of the local contact force distribution. In the C-Gr/*a*-SiO₂ case [Fig. 4(c)], the majority contributors to the λ modes in Γ are further confined spatially (*i.e.*, hot spots). As the conformity between graphene and *a*-SiO₂ has increased, the length scale of morphological mismatch subsequently becomes smaller (i.e., sharper and more confined regions of mismatch can occur) [Fig. 4(f)] and can contribute to the formation of these so-called hot spots. We can therefore hypothesize that the local variance (and specifically, the frequency) of the vdW interaction acting on graphene, which is driven by these morphological differences, serves as a type of disorder that localizes vibrational eigenstates and correspondingly suppresses thermal transport and κ .

IV. CONCLUSIONS

In summary, we demonstrate the importance of the local dampening disorder induced by morphological differences on the suppression of thermal transport in supported graphene. The thermal conductivity of supported graphene is found to be sensitive to both the *a*-SiO₂ substrate surface roughness and graphene conformity with modulation within 500 Wm⁻¹K⁻¹. Our analysis attributes this suppression to increasing non-uniformity of the contact force distribution, which is also independent of the van der Waals coupling strength and internal strain energy. These findings suggest that the thermal conductivity of graphene (and other low-dimensional materials) can be influenced by factors such as lattice mismatch, isotope/chemical doping, or surface functionalization by affecting the uniformity of the force distribution, which will require careful consideration in the future.

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REFERENCES

- S. Ghosh, I. Calizo, D. Teweldebrhan, E. P. Pokatilov, D. L. Nika, A. A. Balandin, W. Bao, F. Miao, and C. N. Lau, Extremely high thermal conductivity of graphene: Prospects for thermal management applications in nanoelectronic circuits. Appl. Phys. Lett. 92, 151911 (2008).
- X. Xu, L. F. C. Pereira, Y. Wang, J. Wu, K. Zhang, X. Zhao, S. Bae, C. Tinh Bui, R. Xie, J. T. L. Thong, B. H. Hong, K. P. Loh, D. Donadio, B. Li, and B. Özyilmaz, Length-dependent thermal conductivity in suspended single-layer graphene. Nat. Commun. 5, 3689 (2014).
- W. Cai, A. L. Moore, Y. Zhu, X. Li, S. Chen, L. Shi, and R. S. Ruoff, Thermal transport in suspended and supported monolayer graphene grown by chemical vapor deposition. Nano Lett. 10, 1645 (2010).
- 4. L. Lindsay and D. A. Broido, Optimized Tersoff and Brenner empirical potential parameters for lattice dynamics and phonon thermal transport in carbon nanotubes and graphene. Phys. Rev. B **81**, 205441 (2010).
- 5. B. Kong, S. Paul, M. Nardelli, and K. Kim, First-principles analysis of lattice thermal conductivity in monolayer and bilayer graphene. Phys. Rev. B **80**, 033406 (2009).

- J. H. Seol, I. Jo, A. L. Moore, L. Lindsay, Z. H. Aitken, M. T. Pettes, X. Li, Z. Yao, R. Huang, D. Broido, N. Mingo, R. S. Ruoff, and L. Shi, Two-dimensional phonon transport in supported graphene. Science 328, 213 (2010).
- B. Qiu and X. Ruan, Reduction of spectral phonon relaxation times from suspended to supported graphene. Appl. Phys. Lett. 100, 193101 (2012).
- 8. D. Singh, J. Murthy, and T. Fisher, Mechanism of thermal conductivity reduction in fewlayer graphene. J. Appl. Phys. **110**, 044317 (2011).
- 9. Z.-Y. Ong and E. Pop, Effect of substrate modes on thermal transport in supported graphene. Phys. Rev. B 84, 075471 (2011).
- E. Paek and G. S. Hwang, A computational analysis of graphene adhesion on amorphous silica. J. Appl. Phys. 113, 164901 (2013).
- S. Plimpton, Fast Parallel Algorithms for Short-Range Molecular Dynamics. J. Comput. Phys. 117, 1 (1995).
- 12. See Supplemental Material at [URL] for additional details on the optimal conformation of graphene, the relationship between graphene corrugation and applied strain, the impact of energetics and forces on thermal conductivity, and phonon participation ratios.
- 13. P. K. Schelling, S. R. Phillpot, and P. Keblinski, Comparison of atomic-level simulation methods for computing thermal conductivity. Phys. Rev. B 65, 144306 (2002).
- 14. F. Mu ller-Plathe, A simple nonequilibrium molecular dynamics method for calculating the thermal conductivity. J. Chem. Phys. **106**, 6082 (1997).
- W. Hoover, Canonical Dynamics: Equilibrium Phase-Space Distributions. Phys. Rev. A 31, 1695 (1985).
- 16. D. K. Efetov and P. Kim, Controlling Electron-Phonon Interactions in Graphene at Ultrahigh Carrier Densities. Phys. Rev. Lett. **105**, 256805 (2010).
- 17. J.-W. Jiang, J. Lan, J.-S. Wang, and B. Li, Isotopic effects on the thermal conductivity of graphene nanoribbons: Localization mechanism. J. Appl. Phys. **107**, 054314 (2010).

- 18. Here, we report only the vertical component of the vdW force for clarity, which contributes more than 90% to the total force
- 19. J. Chen, G. Zhang, and B. Li, Substrate coupling suppresses size dependence of thermal conductivity in supported graphene. Nanoscale **5**, 532 (2013).
- 20. A. Bodapati, P. Schelling, S. Phillpot, and P. Keblinski, Vibrations and thermal transport in nanocrystalline silicon. Phys. Rev. B **74**, 245207 (2006).
- Y. Wang, B. Qiu, and X. Ruan, Edge effect on thermal transport in graphene nanoribbons: A phonon localization mechanism beyond edge roughness scattering. Appl. Phys. Lett. 101, 013101 (2012).